

Form PTO-1449 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					ATTY. DOCKET NO. MI22-1951		PRIORITY SERIAL NO. 09/932,003	
					APPLICANT Cem Basceri			
					PRIORITY FILING DATE August 17, 2001		PRIORITY GROUP 2813	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
W	AA	5,256,455	10/26/93	Numasawa				
	AB	5,459,635	10/17/95	Tomozawa et al.				
	AC	5,596,214	01/21/97	Endo				
	AD	5,618,761	04/08/97	Eguchi et al.				
	AE	5,731,948	03/24/98	Yializis et al.				
	AF	5,776,254	07/07/98	Yuuki et al.				
	AG	5,783,253	07/21/98	Roh				
	AH	5,798,903	8/25/98	Dhote et al.				
	AI	6,043,526	3/28/00	Ochiai				
	AJ	6,046,345	04/04/00	Kadokura et al.				
MP	AK	6,078,492	06/20/00	Huang et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
	AL	EP 0 855 735 A2	29.07.98	Europe (Applied Materials, Inc.)				Yes
	AM	EP 0 957 522 A2	17.11.99	Europe (Matsushita Electric Industrial Co. Ltd.)				No
	AN	WO 98/39497	09/11/98	WIPO (Simpson, et al.)				
	AO	0 474 140 A1	08/30/91	Europe (Kamiyama)				
	AP	WO 99/64645	12/16/99	WIPO (Narwankar, et al.)				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
W	AR	Steve Bilodeau et al., <i>Composition Dependence of the Dielectric Properties of MOCVD Ba_xTiO₃</i> , pp. 1-21 (MRS Fall Meeting 12/01/94).						
W	AS	Steve M. Bilodeau et al., <i>MOCVD BST for High Density DRAM Applications</i> (Preprint for SEMICON/WEST 07/12/95), 2 pages.						
W	AT	Y-C Choi et al., Abstract, <i>Improvements of the Properties of Chemical-Vapor-Deposited (Ba,Sr)TiO₃ Films Through Use of a Seed Layer</i> , 36 J. PN. J. APPL. PHYS. Pt. 1, No. 11, pp. 6824-6828 (1997)						
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W	AA	6,153,898	11/28/00	Watanabe et al				
	AB	6,037,205	03/14/00	Huh, et al.				
	AC	5,470,398	11/28/95	Shibuya, et al.				
	AD	5,254,505	10/19/93	Kamiyama				
	AE	6,156,638	12/05/00	Agarwal et al.				
	AF	6,165,834	12/26/00	Agarwal et al.				
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W	AR	Chung Ming Chu et al., Abstract, <i>Electrical properties and crystal structure of (Ba,Sr)TiO₃ films prepared at low temperatures on a LaNiO₃ electrode by radio-frequency magnetron ...</i> , <i>J. APPLIED PHYSICS LETTERS</i> No. 2, pp. 249-251 (1997).						
W	AS	Kazuhiro Eguchi et al., Abstract, <i>Chemical vapor deposition of (Ba,Sr)TiO₃ thin films for application in gigabit scale dynamic random access memories</i> , <i>14 INTEGRATED FERROELECTRICS</i> Nos. 1-4, Pt. 1, pp. 33-42 (1997).						
W	AT	Q.X. Jia et al., Abstract, <i>Structural and dielectric properties of Ba_{0.9}Sr_{0.1} thin films with an epi-RuO₂ bottom electrode</i> , <i>19 INTEGRATED FERROELECTRICS</i> Nos. 1-4, pp. 111-119 (1998).						
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YB	AR	Takaaki Kawahara et al., <i>(Ba, Sr)TiO_x Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes</i> , 35 J. PN. J.							
		APPL. PHYS. Pt. 1, No. 9B, pp. 4880, 4883 (1996).							
J	AS	Rajesh Khamankar et al., <i>A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for ULSI DRAM Applications</i> , Microelectronics Research Center, Univ. of Texas at Austin, TX (Undated), 2 pages.							
WM	AT	Yong Tae Kim et al., Abstract, <i>Advantages of RuO_x bottom electrode in the dielectric and leakage characteristics of (Ba,Sr)TiO_x capacitor</i> , 35 J. PN. J. APPL. PHYS. Pt. 1, No. 12A, pp. 6153-6156 (1996).							
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	AR		S.H. Paek et al., Abstract, <i>Characterization of MIS capacitor of BST thin films deposited on Si by RF magnetron sputtering</i>						
			Ferroelectric Thin Films V. Symposium, San Francisco, CA, pp. 33-38 (April 7, 1995).						
	AS		N. Takeuchi et al., Abstract, <i>Effect of firing atmosphere on the cubic-hexagonal transition in Ba_{0.9}Sr_{0.1}TiO₃</i> , 98 N IPPON						
			SERAMIKKUS KYOKAI GAKUJUTSU RONBUNSHI No. 8, pp. 836-839 (1990).						
	AT		H. Yamaguchi, et al., Abstract, <i>Reactive coevaporation synthesis and characterization of SrTiO₃ -BaTiO₃ thin films</i> , IEEE						
			International Symposium on Applications of Ferroelectrics, Greenville, SC, pp. 285-288 (August 2, 1992).						
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<p><i>W. H. Lee</i></p> <p>6/14/02</p> <p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>									

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
gpc	AR		S. Yamamichi et al., Abstract, <i>Ba + Sr/Ti ratio dependence of the dielectric properties for (Ba_{1-x}Sr_x)TiO₃ thin films prepared</i>						
			<i>by ion beam sputtering</i> , 64 A PPLIED PHYSICS LETTERS No. 13, pp. 1644-1646 (1994).						
yml	AS		M. Yamamuka et al., Abstract, <i>Thermal-Desorption Spectroscopy of (Ba,Sr)TiO₃ Thin-Films Prepared by Chemical-Vapor-Deposition</i>						
			<i>35 J. OF APPL. PHYS. Pt. 1, No. 2A, pp. 729-735 (1996).</i>						
yml	AT		Arai T., et al.: "Preparation of SrTiO ₃ Films on 8-Inch Wafers . . ." Jap. Journal of Applied Physics. Vol. 35, No. 9B, Part 01, 09/01/96,						
			<i>Pgs. 4875-4879.</i>						
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<i>U</i>	AA	09/388,063		Agarwal et al.			August 30, 1999	
<i>U</i>	AB	09/476,516		Basceri			January 3, 2000	
<i>U</i>	AC	09/580,733		Basceri			May 26, 2000	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>U</i>	AR		Kim, et al.: "Structural and Electrical Properties . . ." Applied Physics Letters, US, American Institute of Physics Vol. 65, No. 15, 10/10/94,					
			Pgs. 1955 - 1957.					
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*Examiner Initial		Document Number	Date	Name		Class	Subclass
YL	AA	5,834,060	11/98	Kawahara et al.			
	AB	5,972,430	10/99	DiMeo, Jr. et al.			
	AC	6,127,218	10/00	Kang			
	AD	6,277,436 B1	08/01	Stauf et al.			
	AE	6,245,652 B1	06/01	Gardner et al.			
YL	AF	6,126,753	10/00	Shinriki et al.			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
YL	AR	B	Basceri, Cem et al., "The Dielectric Response as a Function of Temperature and Film Thickness of Fiber-Textured (Ba,Sr)TiO ₃ Thin				
			Films Grown by Chemical Vapor Deposition", J. Appl. Phys. 82(5), Sept. 1, 1997, pp. 2497-2504.				
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<i>eb</i>	AA	App. SN 09/652,907 (as filed and amended)		C. Basceri et al.			08/31/00
<i>eb</i>	AB	App. SN 09/776,217 (as filed and amended)		C. Basceri			02/02/01
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